

### General Description

- Trench Power AlphaMOS ( $\alpha$ MOS LV) technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

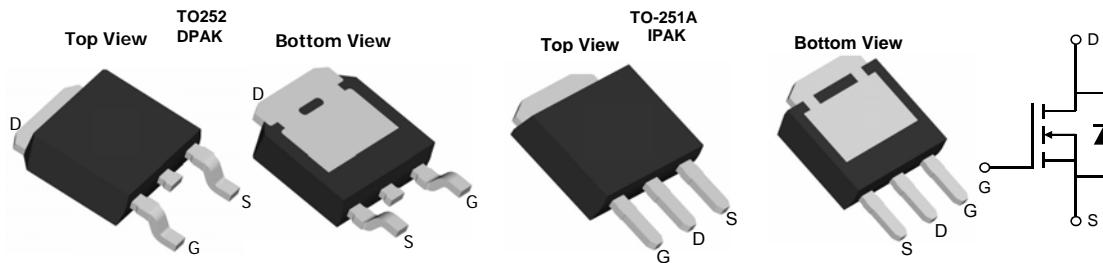
### Product Summary

$V_{DS}$	30V
$I_D$ (at $V_{GS}=10V$ )	70A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 3.1mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 4.8mΩ

### Application

- DC/DC Converters in Computing, Servers, and POL
- Isolated DC/DC Converters in Telecom and Industrial

100% UIS Tested  
100%  $R_g$  Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOD538	TO-252	Tape & Reel	2500
AOI538	TO-251A	Tube	4000

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$	70	A
$T_C=100^\circ C$		54	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	280	
Continuous Drain Current	$I_{DSM}$	34	A
$T_A=70^\circ C$		27	
Avalanche Current <sup>C</sup>	$I_{AS}$	36	A
Avalanche energy $L=0.1mH$ <sup>C</sup>	$E_{AS}$	65	mJ
$V_{DS}$ Spike	$V_{SPIKE}$	36	V
Power Dissipation <sup>B</sup>	$P_D$	93	W
$T_C=25^\circ C$		46	
Power Dissipation <sup>A</sup>	$P_{DSM}$	6.2	W
$T_A=70^\circ C$		4	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>		40	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	1.3	1.6	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{VGS}=0\text{V}$	30			V
$\text{I}_{\text{DSS}}$	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $\text{T}_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$\text{I}_{\text{GSS}}$	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm20\text{V}$			$\pm100$	nA
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.4	1.8	2.2	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$ $\text{T}_J=125^\circ\text{C}$		2.5	3.1	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		3.6	4.5	$\text{m}\Omega$
$\text{g}_{\text{FS}}$	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		91		S
$\text{V}_{\text{SD}}$	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.7	1	V
$\text{I}_{\text{S}}$	Maximum Body-Diode Continuous Current <sup>G</sup>				70	A
<b>DYNAMIC PARAMETERS</b>						
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		2160		pF
$\text{C}_{\text{oss}}$	Output Capacitance			915		pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance			115		pF
$\text{R}_{\text{g}}$	Gate resistance	$\text{f}=1\text{MHz}$	0.9	1.8	2.7	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		30	42	nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			14	20	nC
$\text{Q}_{\text{gs}}$	Gate Source Charge			5.1		nC
$\text{Q}_{\text{gd}}$	Gate Drain Charge			6.3		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		8		ns
$t_{\text{r}}$	Turn-On Rise Time			4		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			29		ns
$t_{\text{f}}$	Turn-Off Fall Time			5.5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		16.5		ns
$\text{Q}_{\text{rr}}$	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		34.2		nC

A. The value of  $\text{R}_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $\text{T}_A=25^\circ\text{C}$ . The Power dissipation  $\text{P}_{\text{DSM}}$  is based on  $\text{R}_{\text{QJA}} \approx 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $175^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $\text{P}_{\text{D}}$  is based on  $\text{T}_{\text{J(MAX)}}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $\text{T}_{\text{J(MAX)}}=175^\circ\text{C}$ .

D. The  $\text{R}_{\text{QJA}}$  is the sum of the thermal impedance from junction to case  $\text{R}_{\text{QJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $\text{T}_{\text{J(MAX)}}=175^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $\text{T}_A=25^\circ\text{C}$ .

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

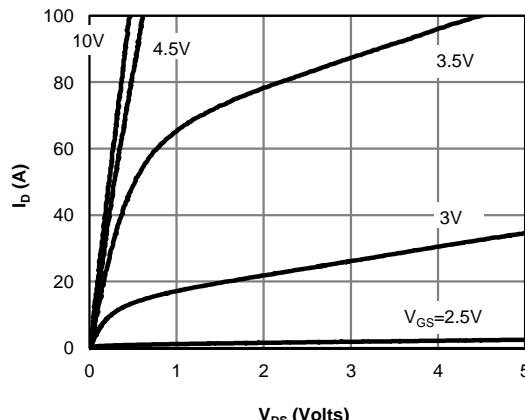


Figure 1: On-Region Characteristics (Note E)

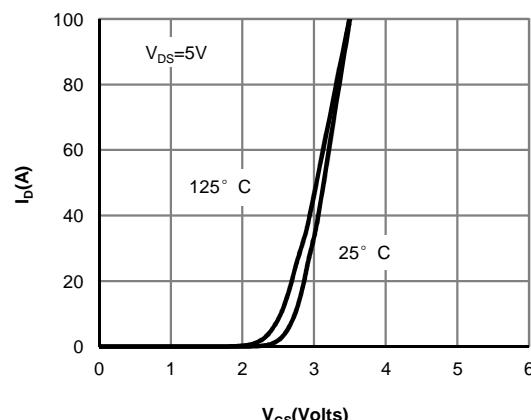


Figure 2: Transfer Characteristics (Note E)

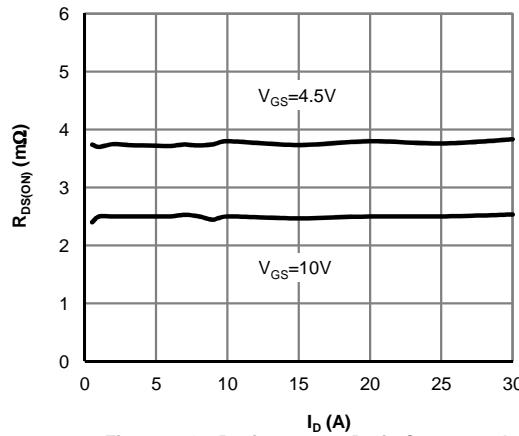


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

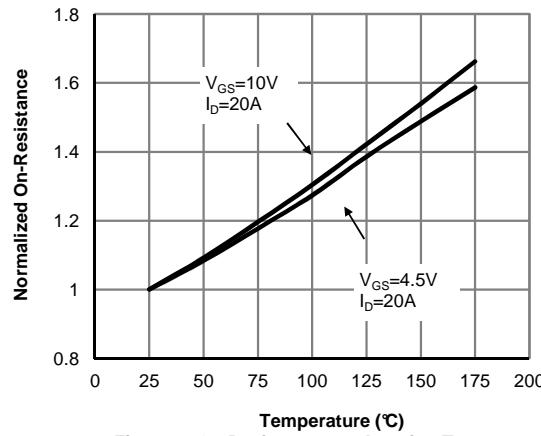


Figure 4: On-Resistance vs. Junction Temperature (Note E)

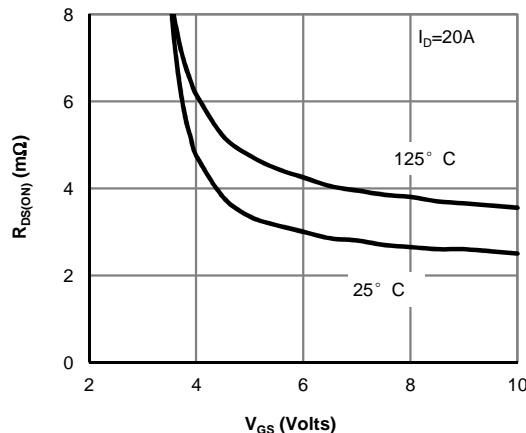


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

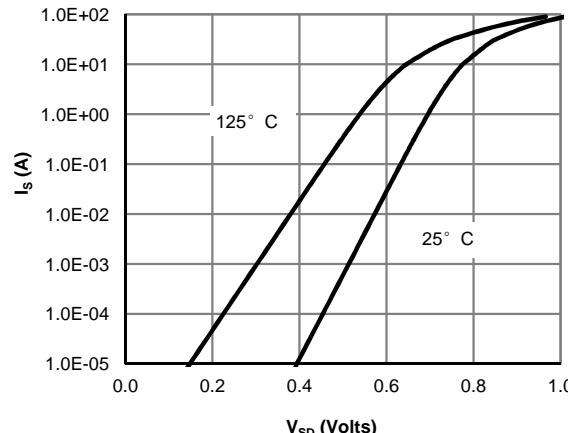


Figure 6: Body-Diode Characteristics (Note E)

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

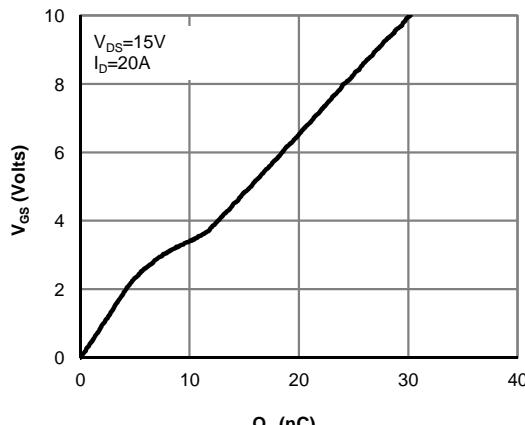


Figure 7: Gate-Charge Characteristics

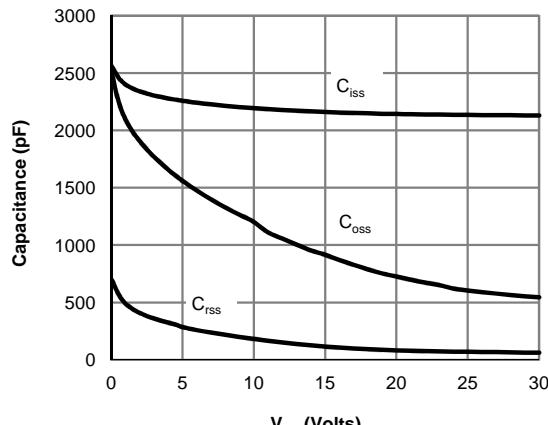


Figure 8: Capacitance Characteristics

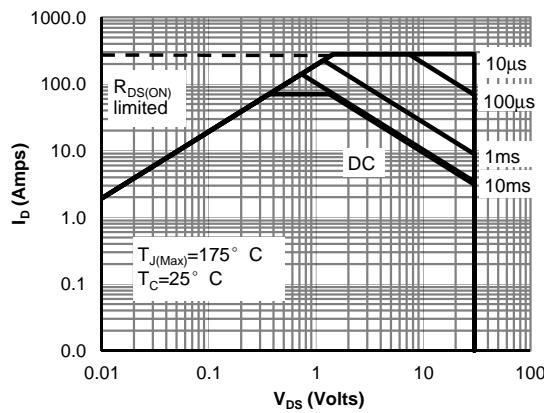


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

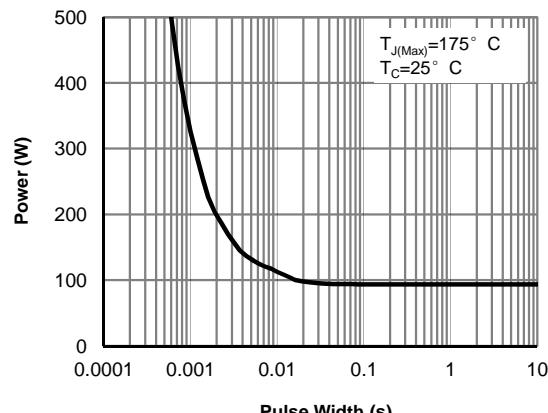


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

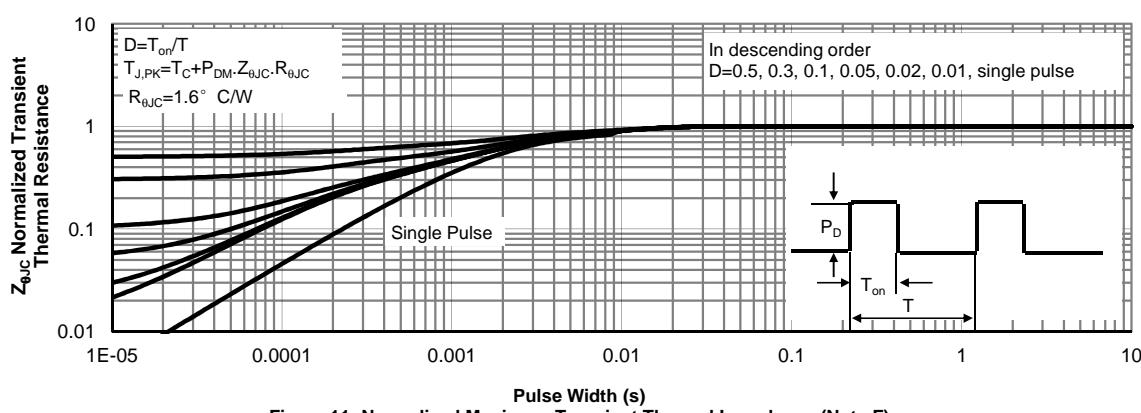


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

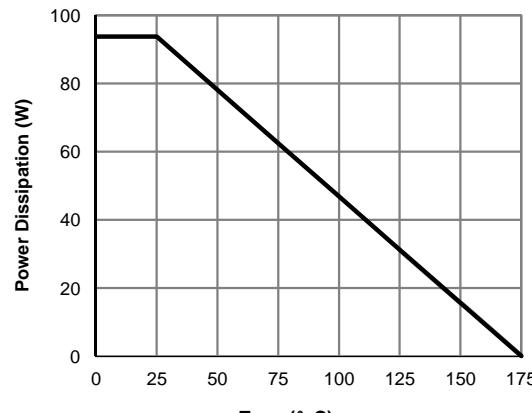
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Figure 12: Power De-rating (Note F)

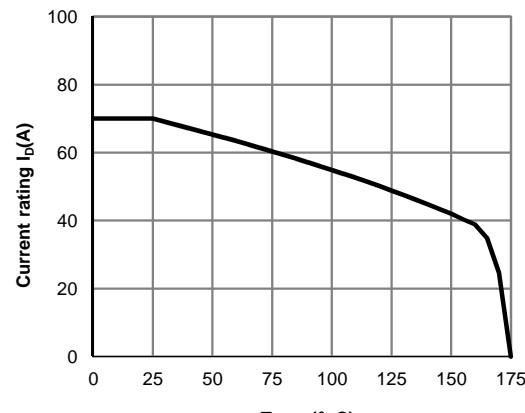


Figure 13: Current De-rating (Note F)

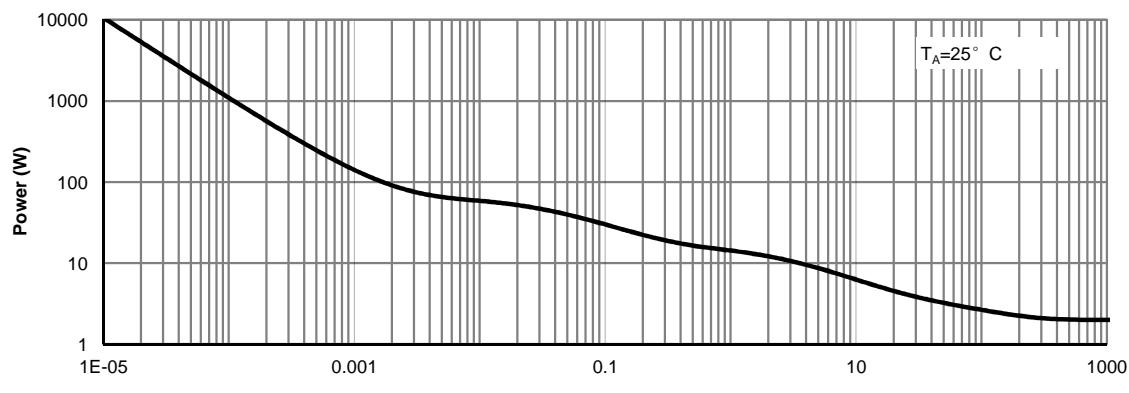


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

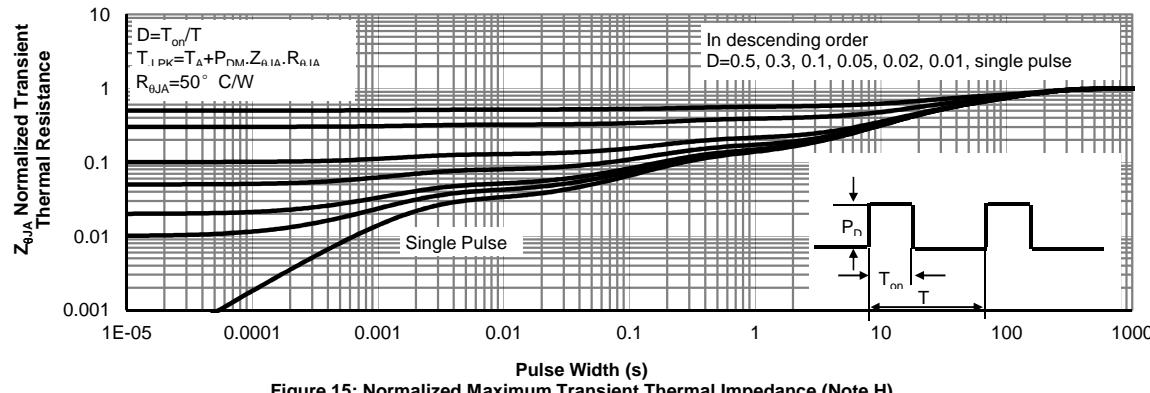
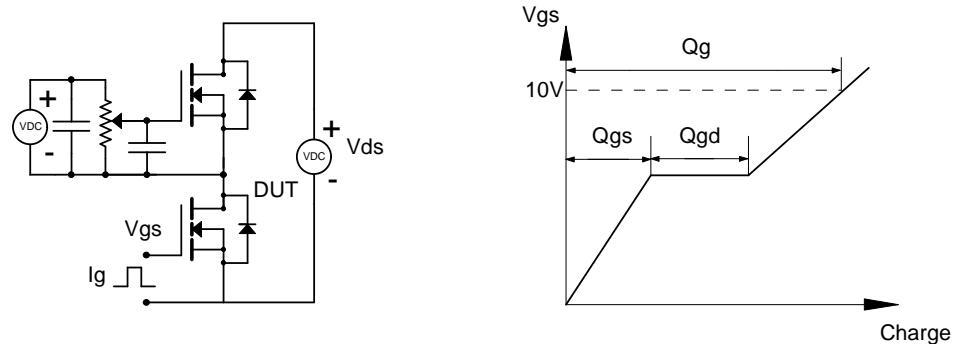
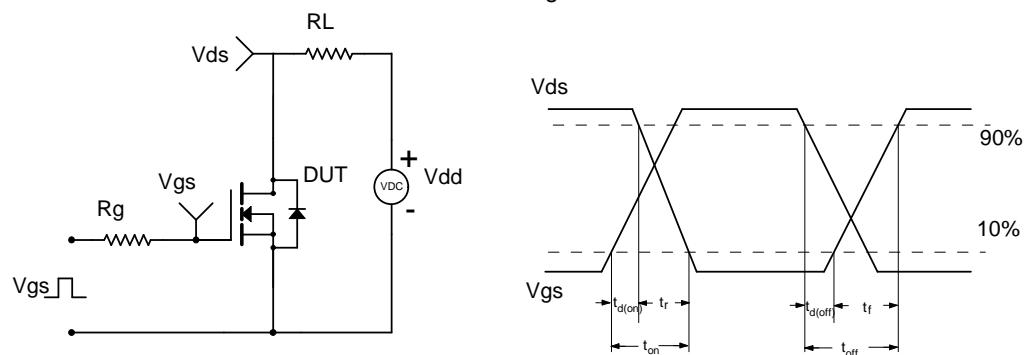


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

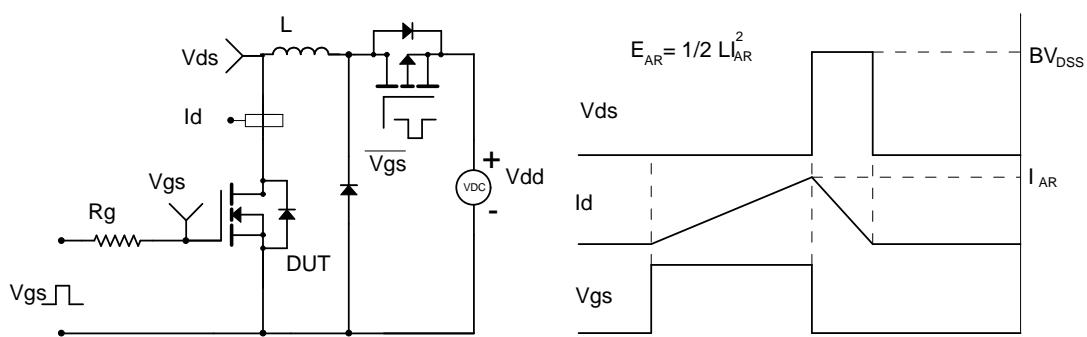
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

